


<b>Search Notes</b>  	<b>Application/Control No.</b>  10574030	<b>Applicant(s)/Patent Under Reexamination</b>  VAN SCHAIJK ET AL.
	<b>Examiner</b>  Hsieh, Hsin-Yi (Steven)	<b>Art Unit</b>  2811

SEARCHED			
Class	Subclass	Date	Examiner
257	326, E29.305	Updated 06/01/11	HH

SEARCH NOTES		
Search Notes	Date	Examiner
Update Search: East search and subclass search	06/01/11	HH
Consulted with the Primary Examiner Shouxiang Hu to re-open the application	05/25/11	HH

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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